ANAB
ANSI National Accreditation Board

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Premier Semiconductor Services LLC
dba Micross

4400 140th Ave. N., Suite 140
Clearwater, FL 33762

Fulfills the requirements of

ISO/IEC 17025:2017

and the

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 06 September 2026
Certificate Number: AT-3126

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Premier Semiconductor Services LLC
dba Micross

4400 140th Ave. N., Suite 140
Clearwater, FL 33762

Gabriela Manugas
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TESTING

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **Premier Semiconductor Services LLC dba Micross** to perform the following AS6171 slash sheet tests:

Valid to: September 6, 2026

Certificate Number: **AT-3126**

Mechanical (Inspection and NDT)

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081 AS6171 AS6171/2 IDEA-STD-1010 Internal Procedure: CLW-WI-0011 MIL-STD-750-2 Test Method: 2068, 2071 MIL-STD-883-2 Test Method: 2009	Electrical, Electronic and Electromechanical (EEE) Components	Multiple Digital Microscopes and Digital Camera, Digital Scale

Mechanical (Inspection and NDT)

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Package Configuration Physical Dimensions	AS6081 AS6171 AS6171/2 IDEA-STD-1010 Internal Procedure: CLW-WI-0011 MIL-STD-750-2 Test Method: 2066 MIL-STD-883-2 Test Method: 2016	Electrical, Electronic and Electromechanical (EEE) Components	Non-contact measurement tool and Calipers
Resistance to Solvents (Remarking & Resurfacing) Scrape Test	AS6081 AS6171 AS6171/2 IDEA-STD-1010 Internal Procedure: CLW-WI-0066 MIL-STD-202-215 MIL-STD-750-2 Test Method: 1022 MIL-STD-883-2 Test Method: 2015	Electrical, Electronic and Electromechanical (EEE) Components	Multiple Microscopes, Hot Plate, X-Acto Knife, and Solvents
Black Top Detection	AS6081 AS6171 AS6171/2 IDEA-STD-1010 Internal Procedure: CLW-WI-0066	Electrical, Electronic and Electromechanical (EEE) Components	Multiple Microscopes, Hot Plate, X-Acto Knife, Dynasolve, and 1-Methyl 2- Pyrrolidinone (1-M-2)
Radiographic Examination / Inspection	AS6081 AS6171 AS6171/5 IDEA-STD-1010 Internal Procedure: CLW-WI-0067 MIL-STD-202-209 MIL-STD-750-2 Test Method: 2076 MIL-STD-883-2 Test Method: 2012	Electrical, Electronic and Electromechanical (EEE) Components	X-Ray Machine, IQI set

Mechanical (Inspection and NDT)

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation and Die Verification	AS6081 AS6171 AS6171/4 IDEA-STD-1010-B Internal Procedure: CLW-WI-0083 MIL-STD-750-2 Test Method: 2072, 2075, 2101, 2102 MIL-STD-883-2 Test Method: 2013	Electrical, Electronic and Electromechanical (EEE) Components	Acid Decapsulator, Kiln, Hot Plates, Dremel, Diagonal Cutters
Solderability	Internal Procedure: CLW-WI-0068 IDEA-STD-1010-B J-STD-002 MIL-STD-202-208 MIL-STD-750-2 Test Method: 2026 MIL-STD-883-2 Test Method: 2003	Electrical, Electronic and Electromechanical (EEE) Components	Steam Ager, Bake Oven, Multiple Microscopes, and Solder Pot
X-Ray Fluorescence (XRF) ROHS/Thickness	AS6081 AS6171 AS6171/3 IDEA-STD-1010 Internal Procedure: CLW-WI-0952 MIL-STD-750-2 Test Method: 2100 MIL-STD-883-2 Test Method: 2037	Electrical, Electronic and Electromechanical (EEE) Components	X-Ray Fluorescence (XRF) machine

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Programming/Flash/Memory	Internal Procedure: CLW-WI-0051	Electrical, Electronic and Electromechanical (EEE) Components	Programmer
Thermal Cycle Test (Temperature Test)	AS6081 AS6171 AS6171/7 IDEA-STD-1010 Internal Procedure: CLW-WI-0955	Electrical, Electronic and Electromechanical (EEE) Components	Temperature Shock/Cycle machine, Temperature Forcing System, Bench Equipment and Automated Test Equipment (ATE)

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
DDR/SRAM	Internal Procedure: CLW-WI-0051	Electrical, Electronic and Electromechanical (EEE) Components	RAM Tester
Electrical Test Electrical, Electronic and Electromechanical (EEE) Components	AS6081 AS6171 AS6171/7 Internal Procedure: CLW-OP-0074	Electrical, Electronic and Electromechanical (EEE) Components	Bench Equipment and Automated Test Equipment (ATE)
Electrical Test (Digital) Microcircuits	MIL-STD-883-3 Class 3000	Electrical, Electronic and Electromechanical (EEE) Components	Bench Equipment and Automated Test Equipment (ATE)
Electrical Test (Linear) Microcircuits	MIL-STD-883-4 Class 4000	Electrical, Electronic and Electromechanical (EEE) Components	Bench Equipment and Automated Test Equipment (ATE)
Transistor Electrical Test Semiconductor Devices	MIL-STD-750-3 Class 3000	Electrical, Electronic and Electromechanical (EEE) Components	Bench Equipment and Automated Test Equipment (ATE)
Diode Electrical test Semiconductor Devices	MIL-STD-750-4 Class 4000	Electrical, Electronic and Electromechanical (EEE) Components	Bench Equipment and Automated Test Equipment (ATE)

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3126.

Jason Stine, Vice President